nexperia

Quarterly Reliability Monitoring Results

Quarters: Q1/2022 to Q4/2023

Based on structural similarity

Supplier		User Part Number						
Nexperia B.V.		PESD18VF1BBSF						
Name of Laboratory Assembly reliability labs		Part Description						
		Nexperia DHAM Protection Std Bipolar						
		BD package						
Test		Test Conditions	Duration	# Lots	# Quantity	# Rejects		
	TEST Pre- and Post-Stress							
# 1	Electrical Test	Tamb = 25 °C	N/A	see below	all parts	see below		
	HTRB	MIL-STD-750-1 M1038 Method A Tj = Tjmax, Vr = 100% of max. datasheet						
# 5	Bias	reverse voltage	1000 hours	17	760	0		
	тс	JESD22-A104						
# 7	Temperature Cycling	-40 °C to 125°C	1000 cycles	157	6880	0		
# 8 or	UHAST Unbiased HAST	JESD22-A118 Tamb = 130 °C, RH = 85 %	96 hours	n.a.	n.a.	n.a.		
	AC	JESD22-A102 Tamb = 121 °C, RH = 100 %						
# 8a	Autoclave	Pressure = 205 kPa (29.7 psia)						
# 9	HAST Highly Accelerated Stress Test	JESD22-A110 Tamb = 130 °C, RH = 85%, VR = 80 % of rated reverse voltage ^[1]	1000 hours	156	6840	0		
# 5	IOL	MIL-STD-750 Method 1037 ton = toff, devices powered to insure ΔT_j =	1000 10013	150	0040	0		
# 10	Intermittent Operating Life		1000 hours	n.a.	n.a.	n.a.		
	RSH	JESD22-A111						
# 20	Resistance to Solder Heat	260 °C ± 5 °C	10 s	n.a.	n.a.	n.a.		
# 21	SD Solderability	J-STD-002		8	240	0		

[1] The maximum applied voltage is limited by test chamber set up and does not exceed 115V.

Calculation of FIT and MTTF

Test considered for FIT calculation: High Temperature Reverse Bias (HTRB, Test # 5) Confidence level 60%, derated to 55 °C, activation energy 0.7 eV, test time 168 to 1000 hours

Wafer Fab T	Technology	Quantity	Rejects	Failure Rate (FIT)	MTTF (hrs)
Nexperia					
DHAM P	Protection Std Bipolar	760	0	5,59	1,79E+08

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